

Srinivas Devayajanam

List of Publications by Year in descending order

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Version: 2024-02-01

15
papers

122
citations

1937685

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h-index

1720034

7
g-index

15
all docs

15
docs citations

15
times ranked

176
citing authors

#	ARTICLE	IF	CITATIONS
1	Understanding light-induced degradation of c-Si solar cells. , 2012, , .		57
2	Surface characteristics and damage distributions of diamond wire sawn wafers for silicon solar cells. AIMS Materials Science, 2016, 3, 669-685.	1.4	15
3	Dissolution of Oxygen Precipitate Nuclei in n-Type CZ-Si Wafers to Improve Their Material Quality: Experimental Results. IEEE Journal of Photovoltaics, 2017, 7, 97-103.	2.5	14
4	Surface Damage Introduced by Diamond Wire Sawing of Si Wafers: Measuring in-depth and the Lateral Distributions for Different Cutting Parameters. Materials Research Society Symposia Proceedings, 2015, 1770, 61-66.	0.1	8
5	Experimental study to separate surface and bulk contributions of light-induced degradation in crystalline silicon solar cells. Emerging Materials Research, 2015, 4, 239-246.	0.7	6
6	Analyses of diamond wire sawn wafers: Effect of various cutting parameters. , 2015, , .		5
7	A new method for rapid measurement of orientations and sizes of grains in multicrystalline silicon wafers. , 2011, , .		4
8	Defect Generation and Propagation in Mc-Si Ingots: Influence on the Performance of Solar Cells. Solid State Phenomena, 2013, 205-206, 55-64.	0.3	3
9	Bulk defect generation during B-diffusion and oxidation of CZ wafers: Mechanism for degrading solar cell performance. , 2014, , .		3
10	A Comparison of Surface Passivation Techniques for Measurement of Minority Carrier Lifetime in Thin Si Wafers: Toward a Stable and Uniform Passivation. Materials Research Society Symposia Proceedings, 2014, 1670, 45.	0.1	3
11	Defects in Epitaxial lift-off Thin Si Films/Wafers and Their Influence on the Solar Cell Performance. Materials Research Society Symposia Proceedings, 2014, 1666, 109.	0.1	2
12	Defect mapping and stress mapping of crystalline silicon using Spectroscopic Ellipsometry. , 2013, , .		1
13	Using minority carrier lifetime measurement to determine saw damage characteristics on Si wafer surfaces. , 2015, , .		1
14	Effect of SiO ₂ passivation on CdTe based solar cells. , 2015, , .		0
15	Notice of Removal Dissolution of oxygen precipitate nuclei in N-type CZ Si wafers to improve their material quality: Experimental results. , 2017, , .		0